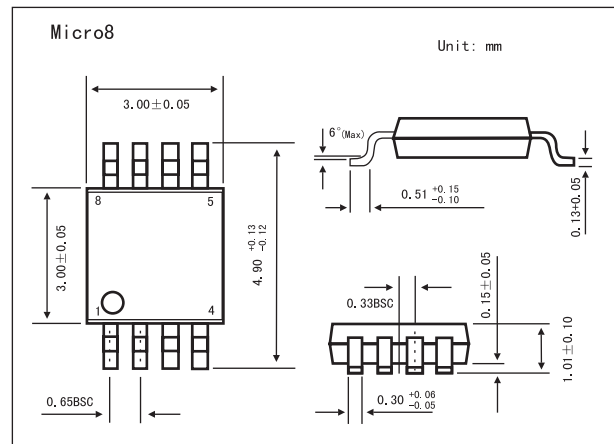
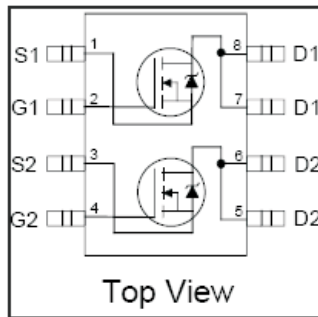


HEXFET[®] Power MOSFET

KRF7530

■ Features

- Trench Technology
- Ultra Low On-Resistance
- Dual N-Channel MOSFET
- Very Small SOIC Package
- Low Profile (<1.1mm)
- Available in Tape & Reel



■ Absolute Maximum Ratings Ta = 25°C

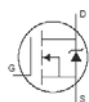
Parameter	Symbol	Rating	Unit
Drain- Source Voltage	V _{DS}	20	A
Continuous Drain Current, V _{GS} @ 4.5V, T _a = 25°C	I _D	5.4	A
Continuous Drain Current, V _{GS} @ 4.5V, T _a = 70°C	I _D	4.3	
Pulsed Drain Current*1	I _{DM}	40	
Power Dissipation T _a = 25°C	P _D	1.3	W
Power Dissipation T _a = 70°C	P _D	0.8	
Linear Derating Factor		10	mW/°C
Single Pulse Avalanche Energy *2	E _{AS}	33	mJ
Gate-to-Source Voltage	V _{GS}	±12	V
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C
Junction-to-Ambient *1	R _{θJA}	100	°C/W

1 Surface mounted on FR-4 board, t ≤ 10sec.

*2 Starting T_J = 25°C, L = 2.6mH, R_G = 25 Ω, I_{AS} = 5.0A.

KRF7530

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250 \mu A$	20			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS} / \Delta T_J$	$I_D = 1mA, \text{Reference to } 25^\circ C$		0.01		V/°C
Static Drain-to-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 5.4A^{*1}$			0.030	Ω
		$V_{GS} = 2.5V, I_D = 4.6A^{*1}$			0.045	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.60		1.2	V
Forward Transconductance	g_{fs}	$V_{DS} = 10V, I_D = 5.4A^{*1}$	13			S
Drain-to-Source Leakage Current	I_{DSS}	$V_{DS} = 16V, V_{GS} = 0V$			1.0	μA
		$V_{DS} = 16V, V_{GS} = 0V, T_J = 70^\circ C$			25	
Gate-to-Source Forward Leakage	I_{GSS}	$V_{GS} = 12V$			-100	nA
Gate-to-Source Reverse Leakage		$V_{GS} = -12V$			100	
Total Gate Charge	Q_g	$I_D = 5.4A$		18	26	nC
Gate-to-Source Charge	Q_{gs}	$V_{DS} = 16V$		3.4	5.1	
Gate-to-Drain ("Miller") Charge	Q_{gd}	$V_{GS} = 4.5V,^{*1}$		3.4	5.1	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 10V$		8.5		ns
Rise Time	t_r	$I_D = 1.0A$		11		
Turn-Off Delay Time	$t_{d(off)}$	$R_G = 6.0 \Omega$		36		
Fall Time	t_f	$R_D = 10 \Omega$		16		
Input Capacitance	C_{iss}	$V_{GS} = 0V$		1310		pF
Output Capacitance	C_{oss}	$V_{DS} = 15V$		180		
Reverse Transfer Capacitance	C_{rss}	$f = 1.0MHz$		150		
Continuous Source Current (Body Diode)	I_S	MOSFET symbol showing the integral reverse p-n junction diode. 			1.3	A
Pulsed Source Current (Body Diode) *2	I_{SM}				40	
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_S = 1.3A, V_{GS} = 0V^{*1}$			1.2	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ C, I_F = 1.3A, V_R = 10V$		19	29	ns
Reverse Recovery Charge	Q_{rr}	$di/dt = 100A/\mu s^{*1}$		13	20	nC

*1 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.

*2 Repetitive rating; pulse width limited by max